S	earch	n Note:	S

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/605,448	BEYER ET AL.	
Examiner	Art Unit	
Dennis Myint	2162	

SEARCHED			
Class	Subclass	Date	Examiner
707	100	8/22/2006	DM
707	1	8/23/2006	DM
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (EPO; JPO; IBM; USPAT)	8/22/2006	DM
EAST (EPO; JPO; IBM; USPAT)	8/23/2006	DM
NPL: ACM	8/22/2006	DM
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